

Features

- N-Channel
20V/27A,
 $R_{DS(ON)} = 10m\Omega(Typ.) @ V_{GS}=4.5V$
 $R_{DS(ON)} = 13m\Omega(Typ.) @ V_{GS}=2.5V$
- P-Channel
-20V/-26A,
 $R_{DS(ON)} = 16m\Omega(Typ.) @ V_{GS}=-4.5V$
 $R_{DS(ON)} = 19m\Omega(Typ.) @ V_{GS}=-2.5V$
- Very low on-resistance
- Fast Switching

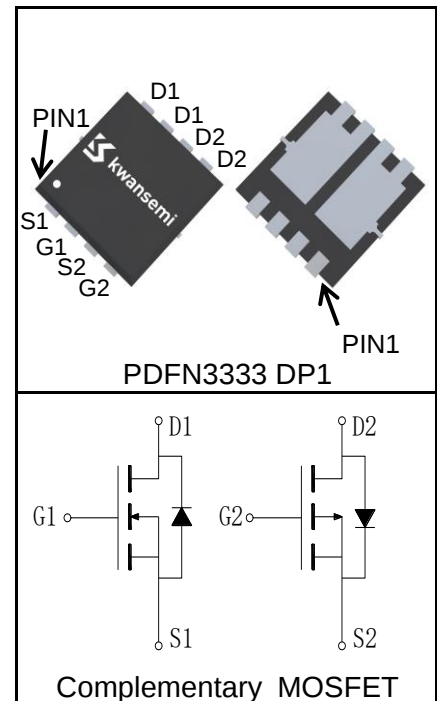
Applications

- Motor Drive Applications



Halogen-Free

Pin Description



Absolute Maximum Ratings

Symbol	Parameter		N-Channel	P-Channel	Unit
Common Ratings (T _A =25°C Unless Otherwise Noted)					
V _{DSS}	Drain-Source Voltage		20	-20	V
V _{GSS}	Gate-Source Voltage		±12	±12	
T _J	Maximum Junction Temperature		150	150	°C
T _J ,T _{STG}	Operating and Storage Temperature Range		-55 to 150	-55 to 150	°C
I _S	Diode Continuous Forward Current	T _C =25°C	27	-26	A
Mounted on Large Heat Sink					
I _{DP} ^①	Pulse Drain Current	T _C =25°C	108	-104	A
I _D ^②	Continuous Drain Current@T _C (V _{GS} =±4.5V)	T _C =25°C	27	-26	A
		T _C =100°C	17	-16	
	Continuous Drain Current@T _A (V _{GS} =±4.5V) ^③	T _A =25°C	12	-10	
		T _A =70°C	9	-8	
P _D	Maximum Power Dissipation@T _C	T _C =25°C	13	20	W
		T _C =100°C	5	8	
	Maximum Power Dissipation@T _A ^③	T _A =25°C	2.8	2.8	
		T _A =70°C	1.8	1.8	
R _{θJC}	Thermal Resistance-Junction to Case		9	6.2	°C/W
R _{θJA} ^③	Thermal Resistance-Junction to Ambient		45	45	°C/W
Drain-Source Avalanche Ratings					
E _{AS} ^④	Avalanche Energy, Single Pulsed		25	72	mJ

Electrical Characteristics ($T_A=25^{\circ}\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Condition	Rating			Unit	
			Min.	Typ.	Max.		
Static Characteristics							
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	N	20			V
		V _{GS} =0V, I _{DS} =-250μA	P	-20			
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =20V, V _{GS} =0V	N			1	μA
				T _J =125°C			
		V _{DS} =-0V, V _{GS} =0V	P			-1	
				T _J =125°C			
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	N	0.4	0.7	1	V
		V _{DS} =V _{GS} , I _{DS} =-250μA	P	-0.4	-0.7	-1	
I _{GSS}	Gate Leakage Current	V _{GS} =±12V, V _{DS} =0V	N			±100	nA
		V _{GS} =±12V, V _{DS} =0V	P			±100	
R _{DS(ON)} ^⑤	Drain-Source On-state Resistance	V _{GS} =4.5V, I _{DS} =5A	N		10	13	mΩ
		V _{GS} =-4.5V, I _{DS} =-5A	P		16	20	
		V _{GS} =2.5V, I _{DS} =-3A	N		13	17	
		V _{GS} =-2.5V, I _{DS} =-3A	P		19	25	
Diode Characteristics							
V _{SD} ^⑤	Diode Forward Voltage	I _{SD} =5A, V _{GS} =0V	N		0.82	1.2	V
		I _{SD} =-5A, V _{GS} =0V	P		-0.84	-1.2	
t _{rr}	Reverse Recovery Time	N-Channel I _{SD} =5A, dI _{SD} /dt=100A/μs	N		6		ns
			P		17		
Q _{rr}	Reverse Recovery Charge	P-Channel I _{SD} =-5A, dI _{SD} /dt=-100A/μs	N		5		nC
			P		14		
Dynamic Characteristics ^⑥							
R _G	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1MHz	N		3.1		Ω
			P		7.7		
C _{iss}	Input Capacitance	N-Channel V _{GS} =0V,V _{DS} =10V, Frequency=200KHz	N		700		pF
			P		1850		
C _{oss}	Output Capacitance		N		115		
			P		205		
C _{rss}	Reverse Transfer Capacitance		N		105		
			P		195		

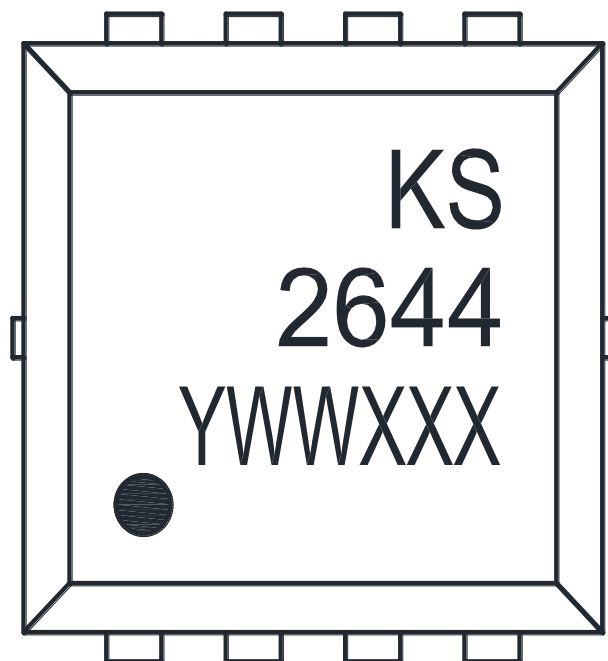
Electrical Characteristics ($T_A=25^{\circ}\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Condition	Rating			Unit
			Min.	Typ.	Max.	
Dynamic Characteristics ^⑥						
t _{d(ON)}	Turn-on Delay Time	N-Channel V _{DD} =10V, I _{DS} =5A, V _{GEN} =4.5V, R _G =3Ω	N		8	ns
			P		15	
t _r	Turn-on Rise Time		N		7	
			P		21	
t _{d(OFF)}	Turn-off Delay Time	P-Channel V _{DD} =-10V, I _{DS} =-5A, V _{GEN} = -4.5V, R _G =3Ω	N		32	
			P		37	
t _f	Turn-off Fall Time		N		8	
			P		15	
Gate Charge Characteristics ^⑥						
Q _g	Total Gate Charge	N-Channel V _{DS} =10V, V _{GS} =4.5V, I _{DS} =5A	N		9.5	nC
			P		11	
Q _{gs}	Gate-Source Charge	P-Channel V _{DS} =-10V, V _{GS} = -4.5V, I _{DS} =-5A	N		1	
			P		1.3	
Q _{gd}	Gate-Drain Charge		N		2.9	
			P		3.2	

- Notes:
- ① Pulse width limited by safe operating area.
 - ② Calculated continuous current based on maximum allowable junction temperature.
 - ③ When mounted on 1 inch square copper board, $t \leq 10\text{sec}$. The value in any given application depends on the user's specific board design.
 - ④ Limited by T_{Jmax} . Starting $T_J = 25^{\circ}\text{C}$, N Channel: $I_{ASmax} = 10\text{A}$, $L = 0.5\text{mH}$, $V_{DD} = 10\text{V}$, $R_G = 25\Omega$, $V_{GS} = 4.5\text{V}$, Part not recommended for use above this value. 100% Final Test at $I_{AS} = 6\text{A}$, $L = 0.5\text{mH}$. P-Channel: $I_{ASmax} = -17\text{A}$, $L = 0.5\text{mH}$, $V_{DD} = -10\text{V}$, $R_G = 25\Omega$, $V_{GS} = -4.5\text{V}$, Part not recommended for use above this value. 100% Final Test at $I_{AS} = -9\text{A}$, $L = 0.5\text{mH}$.
 - ⑤ Pulse test; Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
 - ⑥ Guaranteed by design, not subject to production testing.

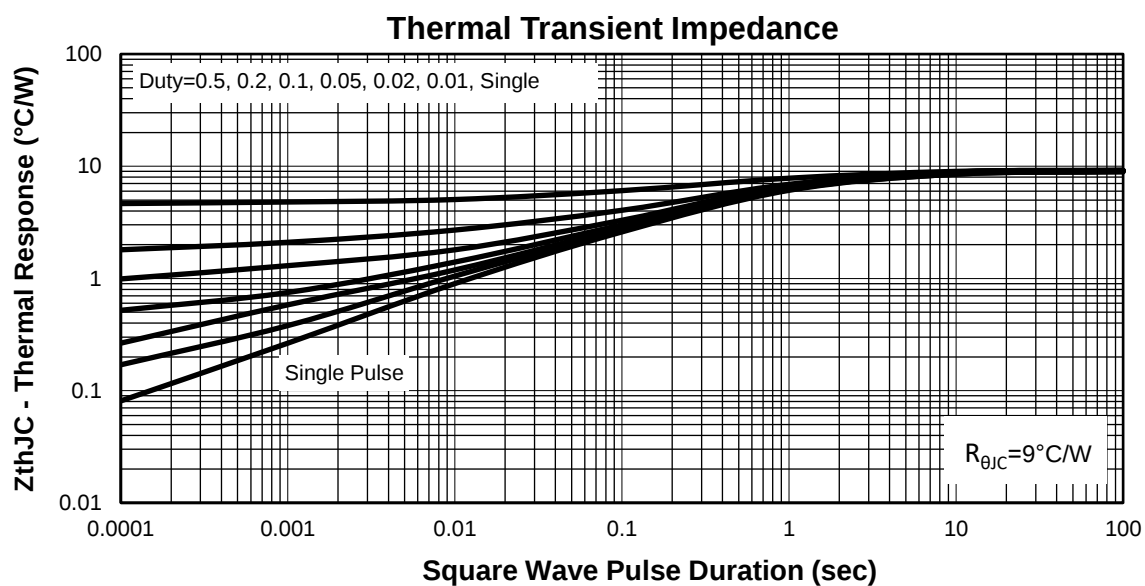
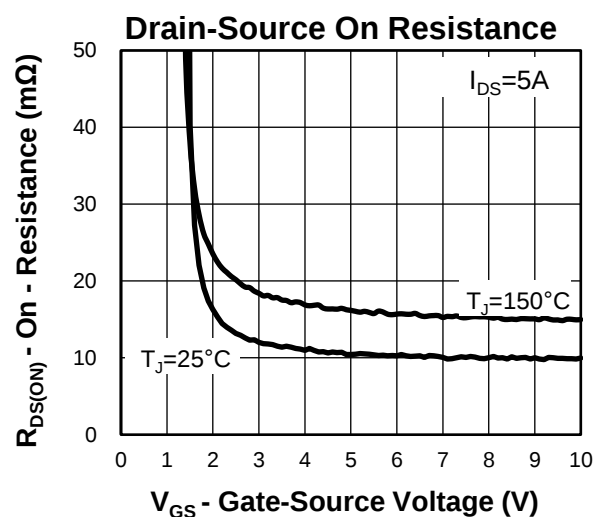
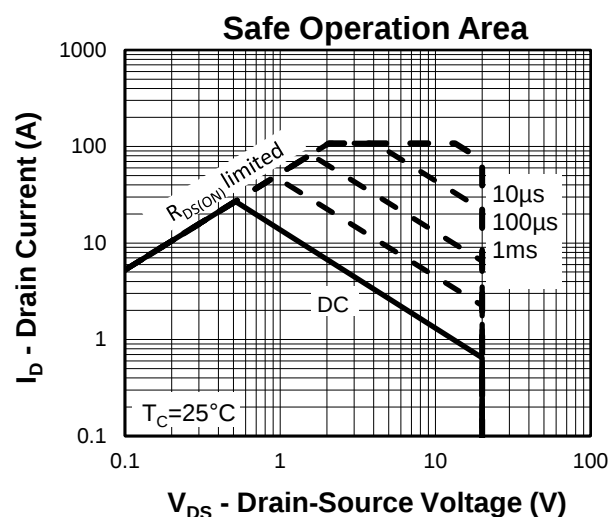
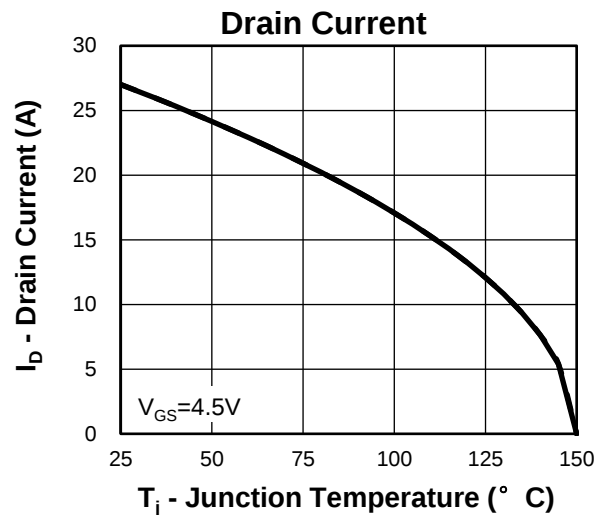
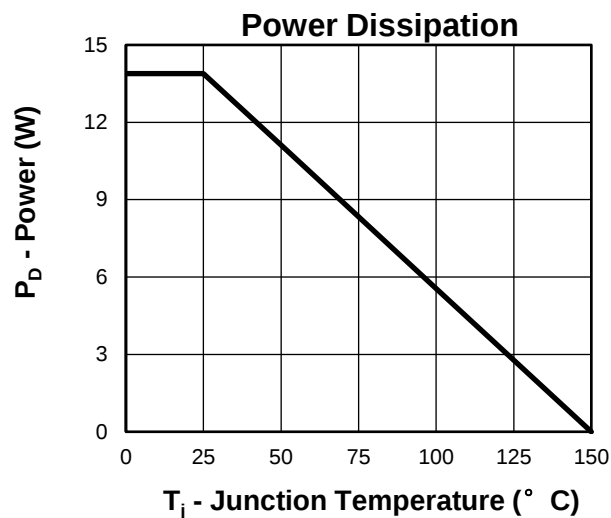
Ordering and Marking Information

Device	Package	Packaging	Quantity	Reel Size	Tape width
KS2644MA	PDFN3333 DP1	Tape&Reel	5000	13"	12mm

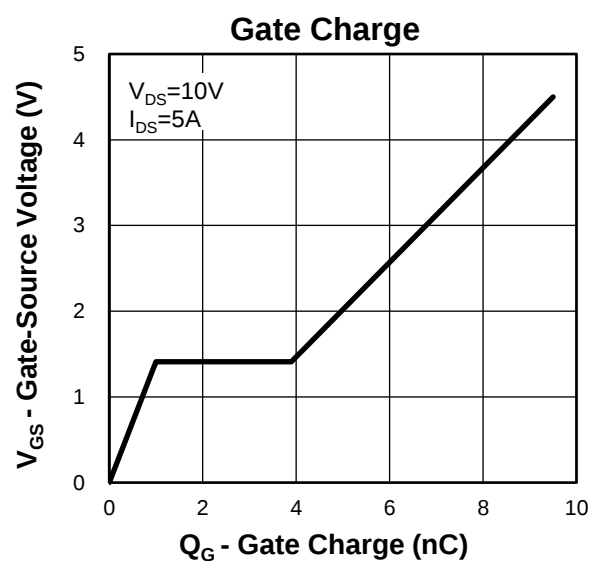
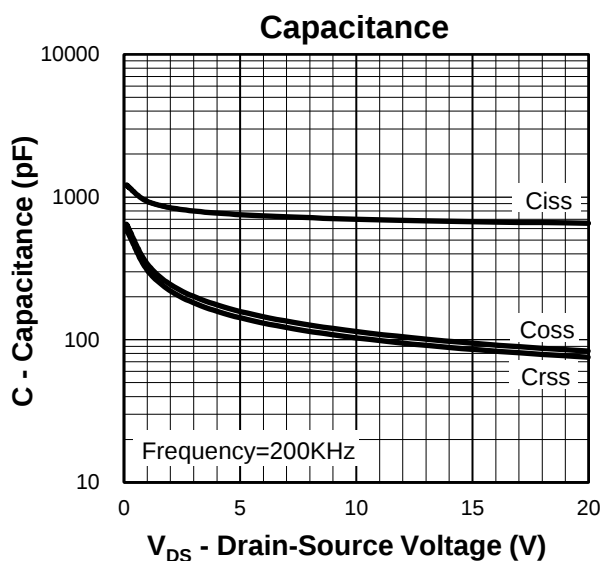
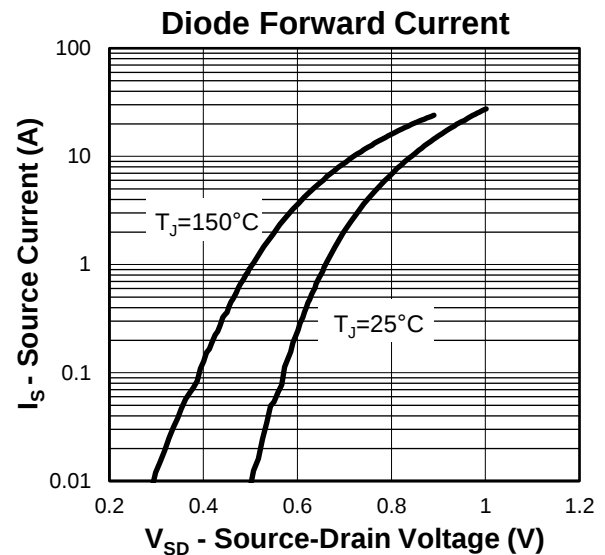
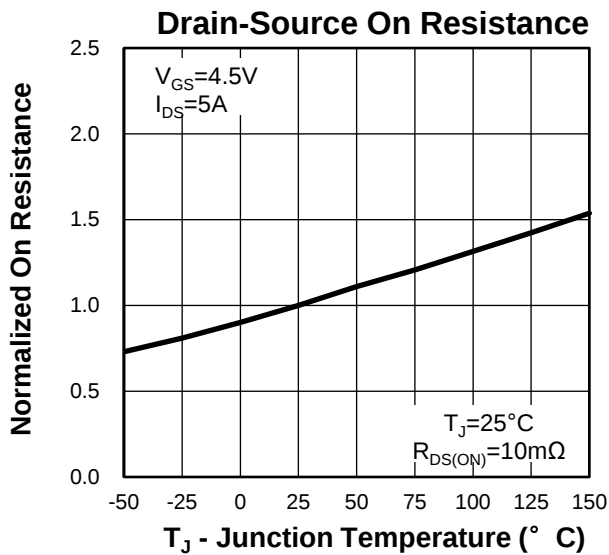
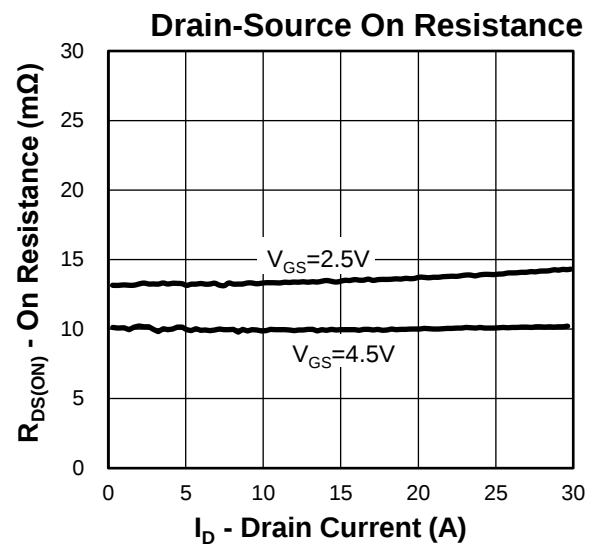
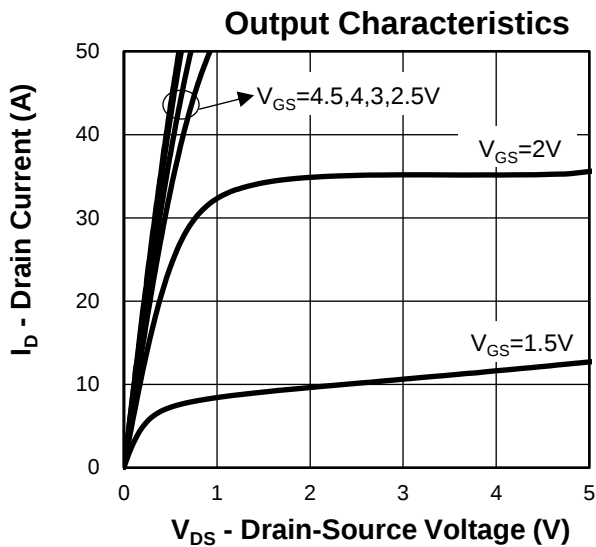


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2nd Line: Part Number(2644)
3rd Line: Lot Number(YWWXXX)

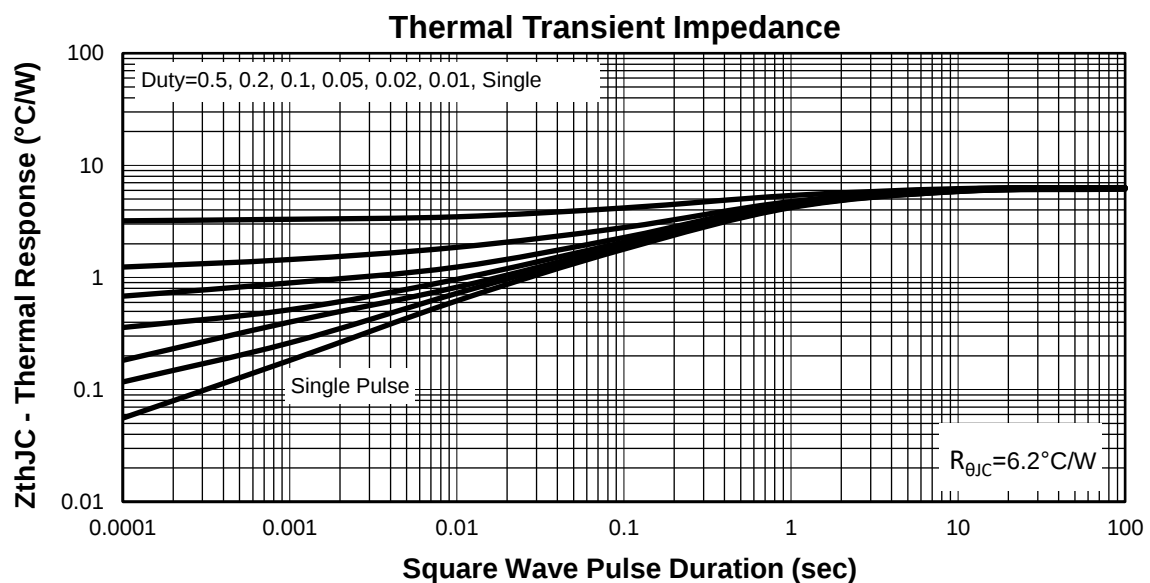
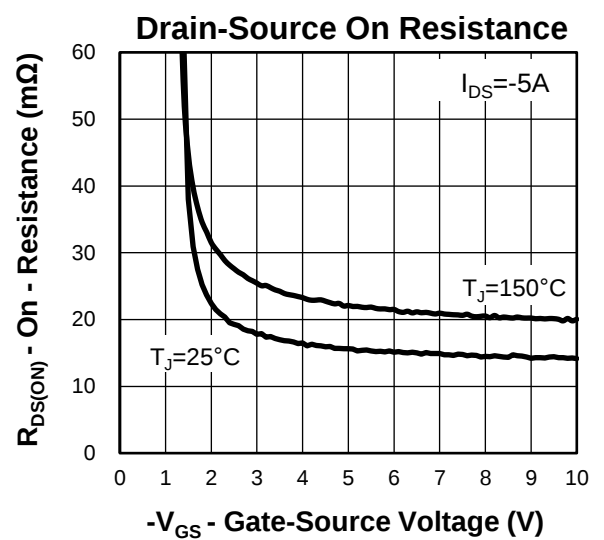
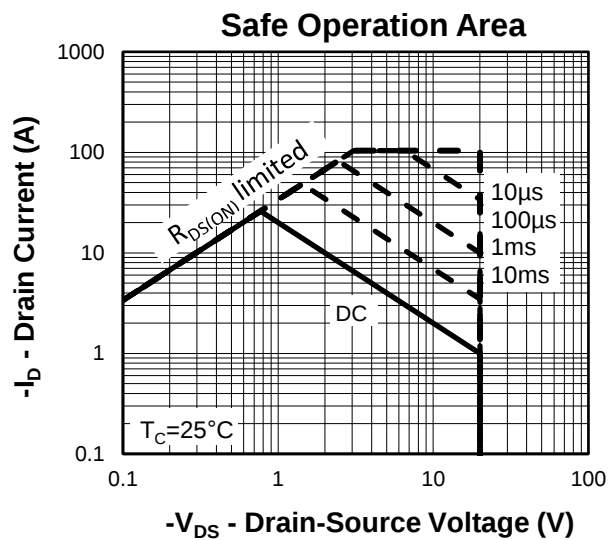
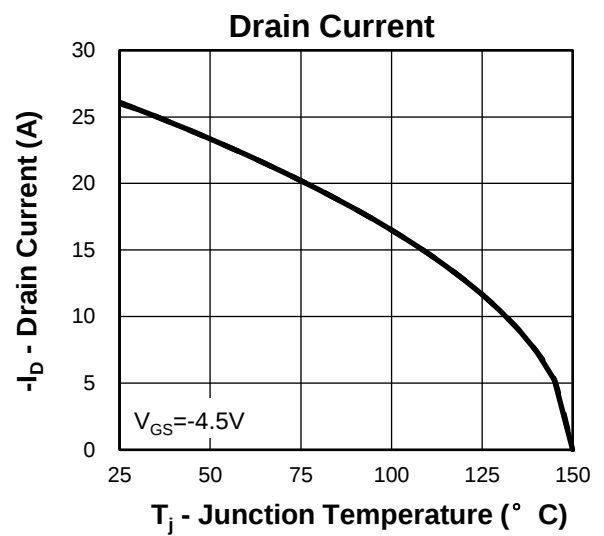
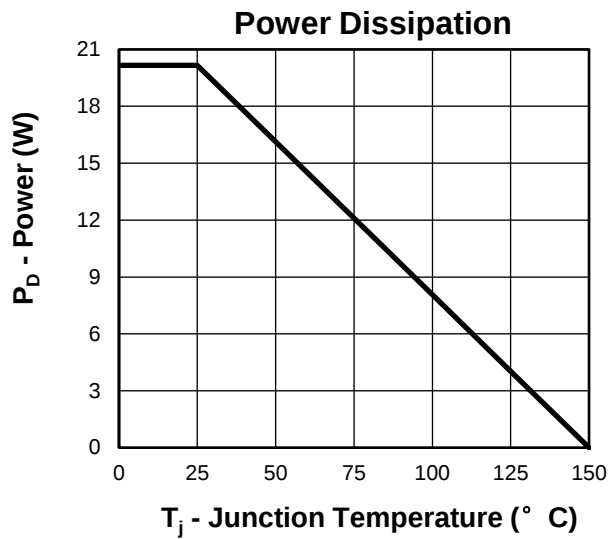
Typical Characteristics(N-Channel)



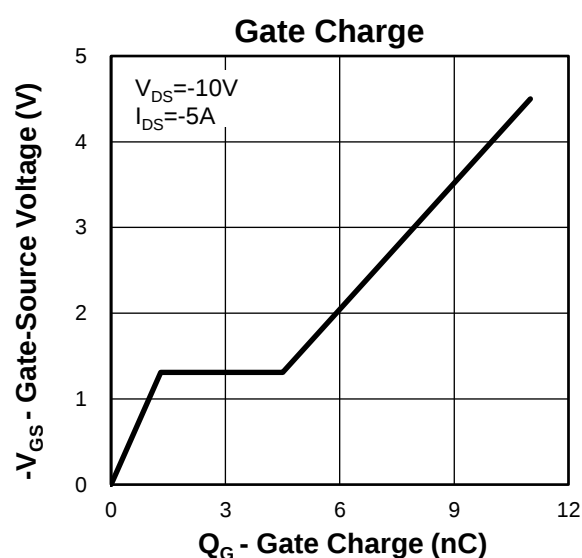
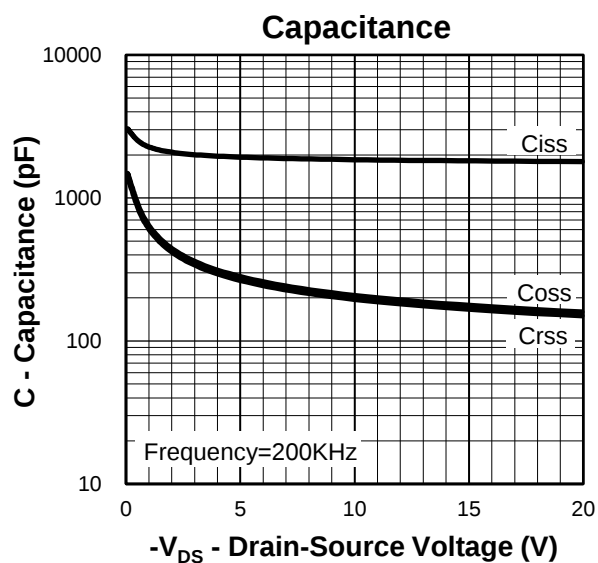
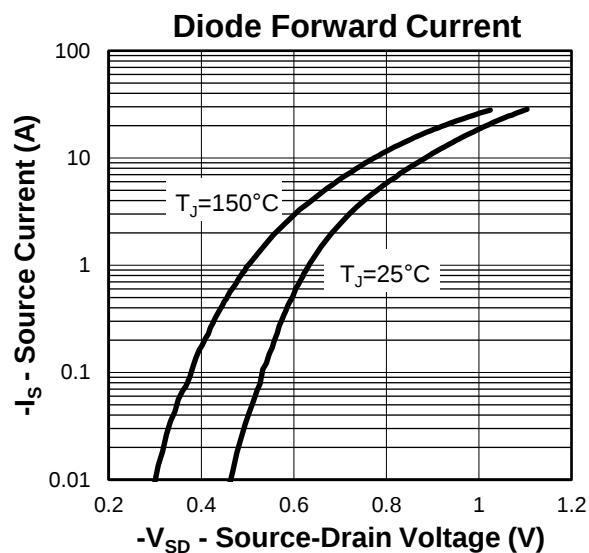
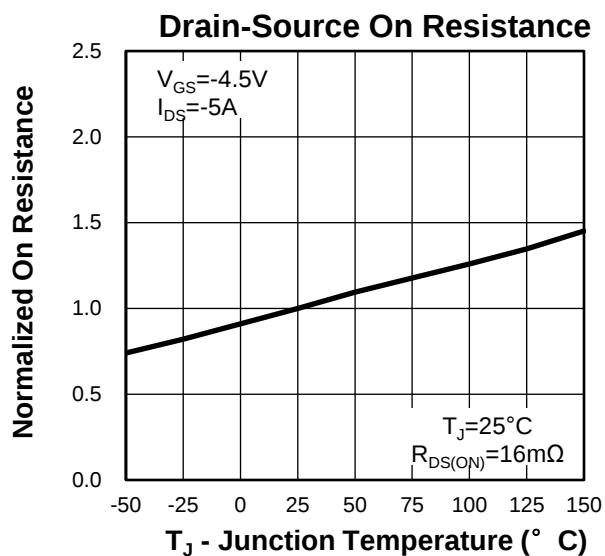
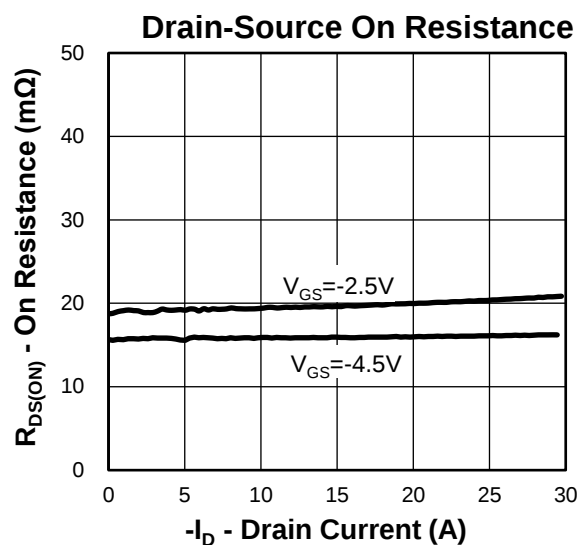
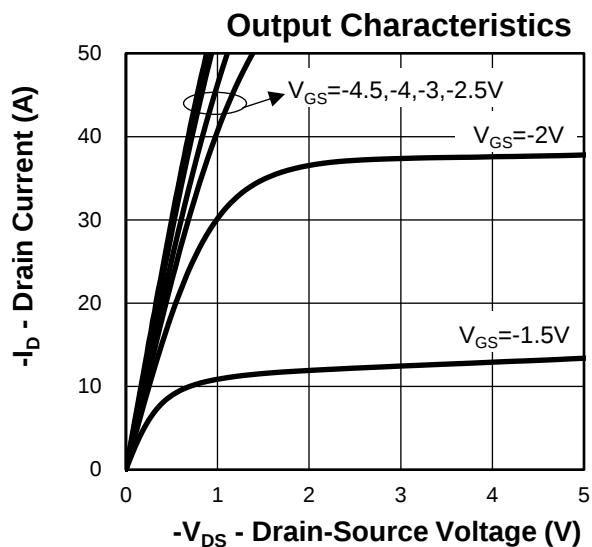
Typical Characteristics(N-Channel)

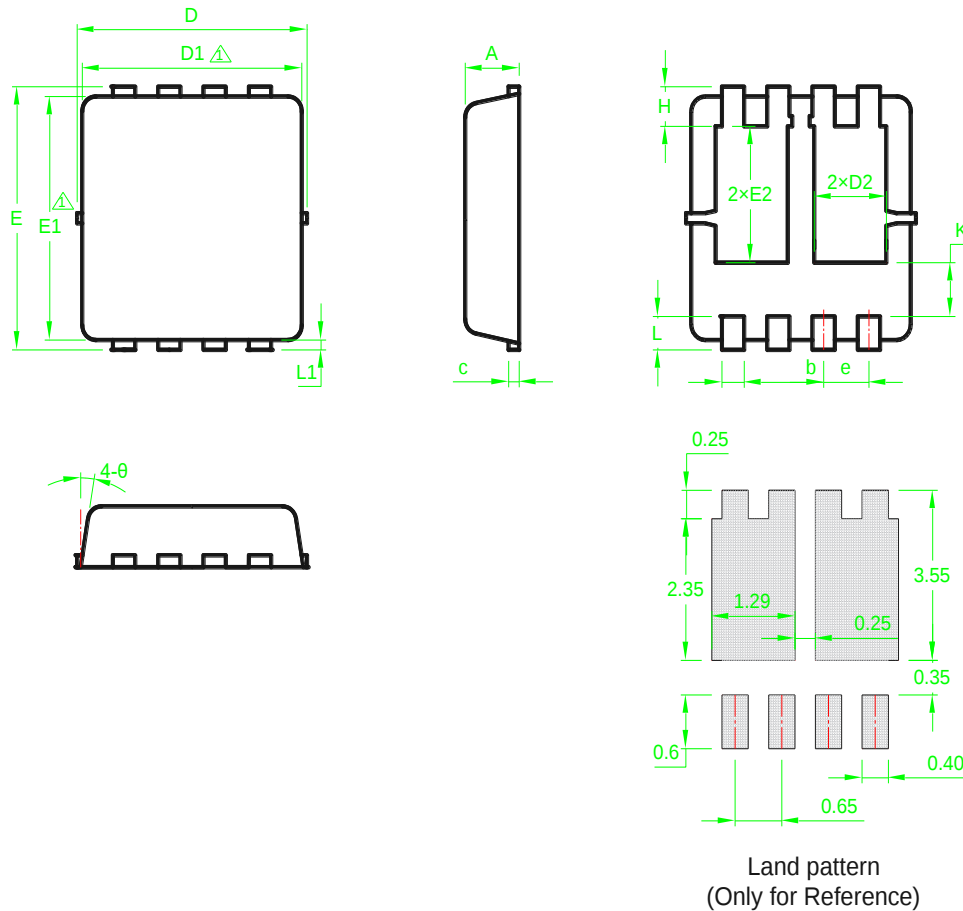


Typical Characteristics(P-Channel)



Typical Characteristics(P-Channel)

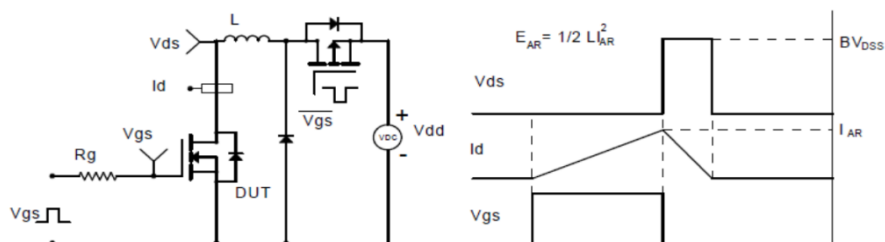


Package Information
PDFN3333 DP1


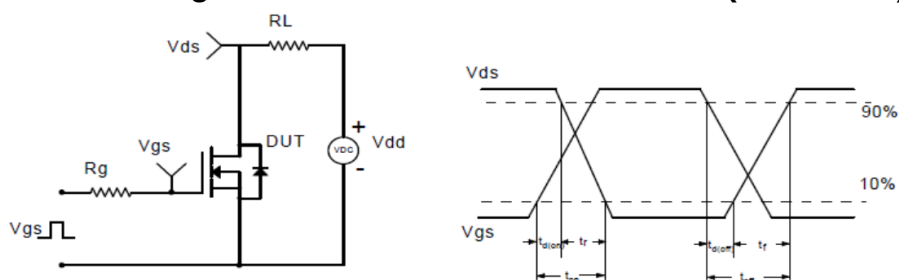
SYMBOL	MM			INCH			SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX		MIN	NOM	MAX	MIN	NOM	MAX
A	0.70	0.80	0.90	0.028	0.031	0.035	E2	1.65	*	1.95	0.065	*	0.077
b	0.25	0.30	0.35	0.010	0.012	0.014	e	0.65BSC			0.026BSC		
c	0.10	0.15	0.25	0.004	0.006	0.010	H	0.30	0.40	0.50	0.012	0.016	0.020
D	3.30BSC			0.130BSC			K	0.50	*	0.80	0.020	*	0.031
D1	3.00	3.15	3.25	0.118	0.124	0.128	L	0.30	0.40	0.50	0.012	0.016	0.020
D2	0.80	1.00	1.20	0.031	0.039	0.047	L1	0.10	0.15	0.20	0.004	0.006	0.008
E	3.30BSC			0.130BSC			θ	8°	*	12°	8°	*	12°
E1	2.90	3.05	3.20	0.114	0.120	0.126							

△ Dimensions D1 and E1 do not include mold flash protrusions or gate burrs.

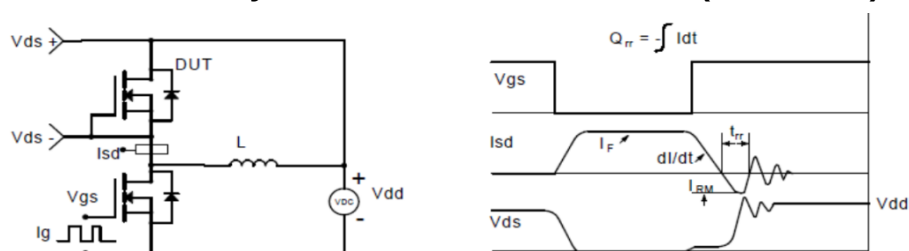
Avalanche Test Circuit and Waveforms(N-Channel)



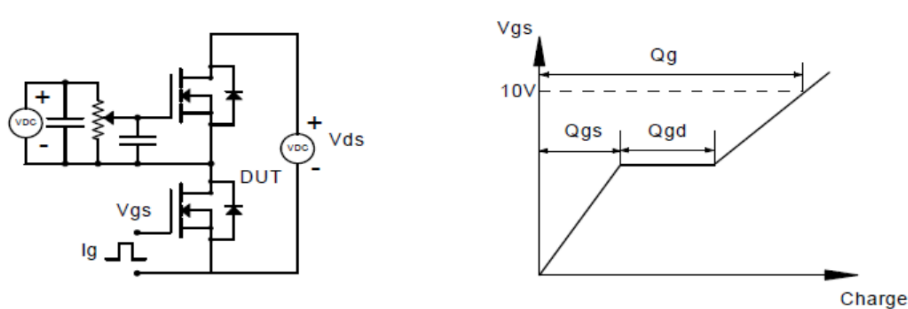
Switching Time Test Circuit and Waveforms(N-Channel)



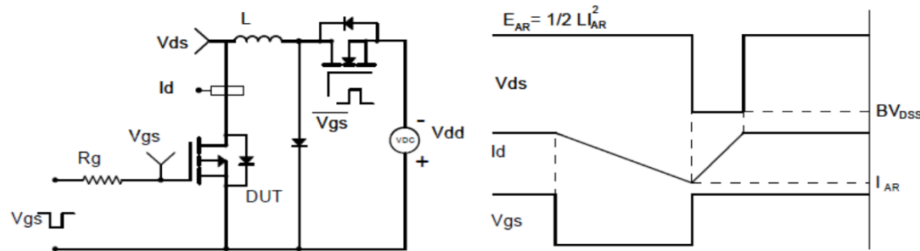
Diode Recovery Test Circuit and Waveforms(N-Channel)



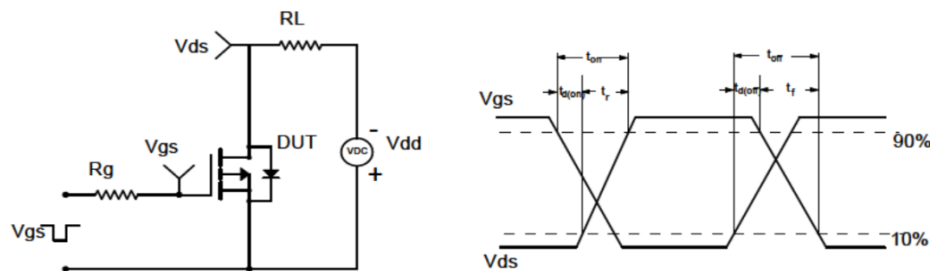
Gate Charge Test Circuit and Waveform(N-Channel)



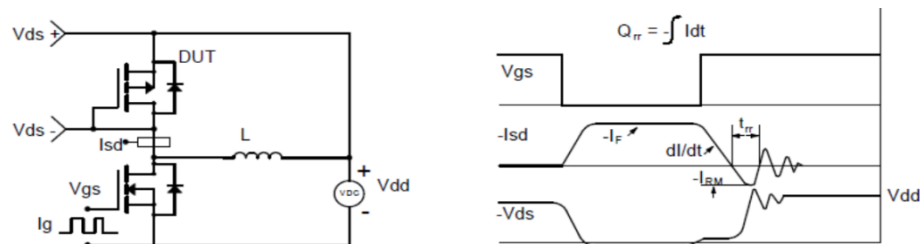
Avalanche Test Circuit and Waveforms(P-Channel)



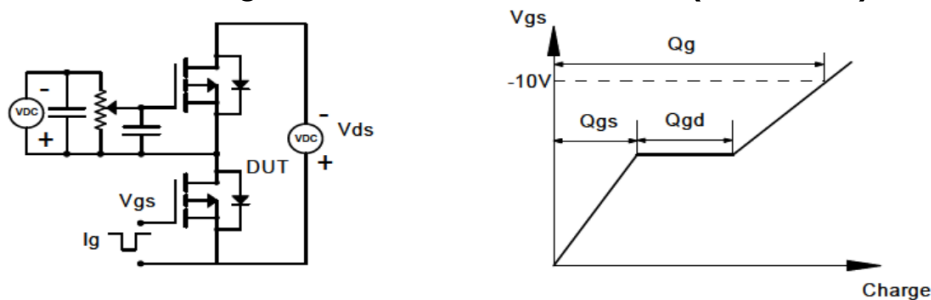
Switching Time Test Circuit and Waveforms(P-Channel)



Diode Recovery Test Circuit and Waveforms(P-Channel)



Gate Charge Test Circuit and Waveform(P-Channel)



Customer Service

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